

AMENDMENTS TO THE SPECIFICATION:

Please replace the paragraph beginning at page 1, line 19, with the following rewritten paragraph:

1 As an example, an integrated circuit ~~a specific ASP Wireless device~~
2 containing an Analog to Digital Converter (ADC) typically requires test
3 verification. The test verification of two key parameters F(full scale)set and
4 Z(zero)set is usually considered ~~are critical in such cases~~. Unfortunately, contact
5 resistance during bump probing is often too high to correctly validate the
6 operation of the ADC for these two parameters.